

October 1988 Revised March 1999

# 74F2244 Octal Buffer/Line Driver with 25 $\Omega$ Series Resistors in Outputs

#### **General Description**

The F2244 is an octal buffer/line driver designed to drive the capacitive inputs of MOS memory drivers, address drivers, clock drivers and bus-oriented transmitters/receivers.

The  $25\Omega$  series resistors in the outputs reduce ringing and eliminate the need for external resistors.

#### **Features**

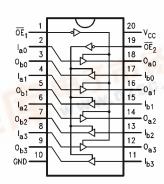
- 3-STATE outputs drive bus lines or buffer memory address registers
- 12 mA source current
- $\blacksquare$  25 $\Omega$  series resistors in outputs eliminate the need for external resistors.
- Designed to drive the capacitive inputs of MOS devices
- Guaranteed 4000V minimum ESD protection

#### **Ordering Code:**

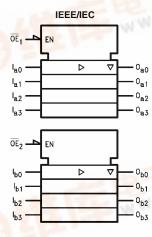
Order Number	Package Number	Package Description
74F2244SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F2244MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F2244PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

#### **Connection Diagram**



#### **Logic Symbol**





### **Unit Loading/Fan Out**

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>	
		HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>	
$\overline{OE}_1$ , $\overline{OE}_2$	3-STATE Output Enable Input (Active LOW)	1.0/1.667	20 μA/–1 mA	
OE <sub>2</sub>	3-STATE Output Enable Input (Active HIGH)	1.0/1.667	20 μA/–1 mA	
I <sub>an</sub> , I <sub>bn</sub>	Inputs	1.0/2.667 (Note 1)	20 μA/–1.6 mA	
O <sub>an</sub> ,O <sub>bn</sub>	Outputs	750/20	–15 mA/12 mA	

Note 1: Worst-case F2244 disabled

#### **Truth Table**

OE <sub>1</sub>	I <sub>an</sub>	O <sub>an</sub>	OE <sub>2</sub>	I <sub>bn</sub>	O <sub>bn</sub>	
Н	X	Z	Н	X	Z	
L	Н	Н	L	Н	Н	
L	L	L	L	L	L	

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance

#### **Absolute Maximum Ratings**(Note 2)

## **Recommended Operating Conditions**

 $\begin{array}{ll} \mbox{Storage Temperature} & -65\mbox{°C to } +150\mbox{°C} \\ \mbox{Ambient Temperature under Bias} & -55\mbox{°C to } +125\mbox{°C} \\ \end{array}$ 

Ambient Temperature under Bias -55°C to +125°C

Junction Temperature under Bias -55°C to +150°C

 $V_{CC}$  Pin Potential to Ground Pin -0.5V to +7.0VInput Voltage (Note 3) -0.5V to +7.0VInput Current (Note 3) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with  $V_{CC} = 0V$ )

 $\begin{array}{ll} \mbox{Standard Output} & -0.5\mbox{V to V}_{\mbox{CC}} \\ \mbox{3-STATE Output} & -0.5\mbox{V to } +5.5\mbox{V} \end{array}$ 

Current Applied to Output

in LOW State (Max) twice the rated  $I_{OL}$  (mA) ESD Last Passing Voltage (Min) 4000V

Free Air Ambient Temperature  $0^{\circ}\text{C} \text{ to } +70^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

**Note 2:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

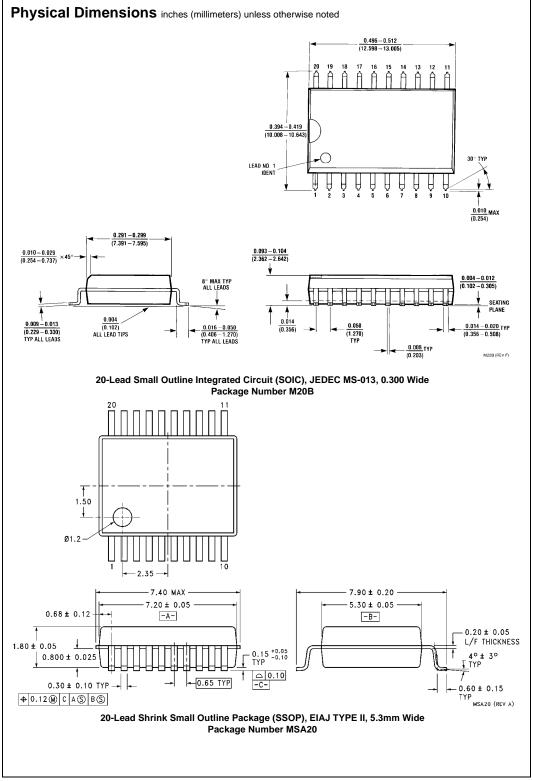
Note 3: Either voltage limit or current limit is sufficient to protect inputs.

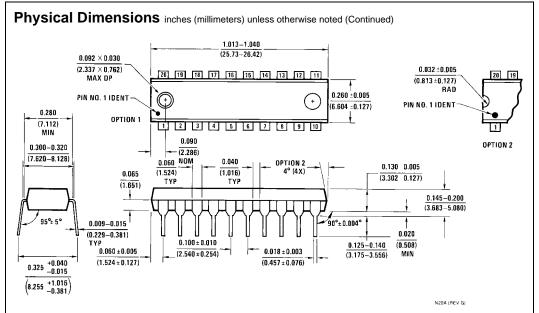
#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	v <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V		Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage 10% V <sub>C0</sub>	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
	10% V <sub>CC</sub>	2.0					$I_{OH} = -15 \text{ mA}$
	5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA}$
V <sub>OL</sub>	Output LOW Voltage			0.50	V	Min	I <sub>OL</sub> = 1 mA
				0.75			$I_{OL} = 12 \text{ mA}$
I <sub>IH</sub>	Input HIGH Current			5.0	μΑ	Max	V <sub>IN</sub> = 2.7V
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7.0	μΑ	Max	V <sub>IN</sub> = 7.0V
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC}$
V <sub>ID</sub>	Input Leakage	4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$
	Test						All other pins grounded
I <sub>OD</sub>	Output Leakage			3.75	μΑ	0.0	$V_{IOD} = 150 \text{ mV}$
	Circuit Current						All other pins grounded
I <sub>IL</sub>	Input LOW Current			-1.0	mA	Max	$V_{IN} = 0.5V (\overline{OE}_1, \overline{OE}_2, OE_2)$
				-1.6			$V_{IN} = 0.5V (I_n)$
I <sub>OZH</sub>	Output Leakage Current			50	μА	Max	V <sub>OUT</sub> = 2.7V
I <sub>OZL</sub>	Output Leakage Current			-50	μА	Max	V <sub>OUT</sub> = 0.5V
Ios	Output Short-Circuit Current	-100		-225	mA	Max	V <sub>OUT</sub> = 0V
I <sub>CCH</sub>	Power Supply Current		40	60	mA	Max	V <sub>O</sub> = HIGH
I <sub>CCL</sub>	Power Supply Current		60	90	mA	Max	$V_O = LOW$
I <sub>CCZ</sub>	Power Supply Current		60	90	mA	Max	V <sub>O</sub> = HIGH Z

#### **AC Electrical Characteristics**

Symbol	Parameter	$T_A = +25^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$ $C_L = 50 \text{ pF}$			$T_A = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	1
t <sub>PLH</sub>	Propagation Delay	1.5		7.0	2.0	6.5	1.5	7.0	ns
t <sub>PHL</sub>	Data to Output	2.5		8.0	2.0	7.0	2.0	8.0	
t <sub>PZH</sub>	Output Enable Time	1.5		9.0	2.0	7.0	1.0	9.5	
$t_{PZL}$		2.5		11.5	2.0	8.5	2.5	12.0	ns
t <sub>PHZ</sub>	Output Disable Time	1.5		9.0	2.0	7.0	1.0	9.5	
$t_{PLZ}$		1.5		8.5	2.0	7.5	1.5	9.5	





20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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